## Checkpointing strategies for parallel jobs

Marin BOUGERET, Henri CASANOVA, Mikaël RABIE, Yves ROBERT, and Frédéric VIVIEN

> ENS Lyon & INRIA, France University of Hawai'i at Mānoa, USA University of Montpellier, France

#### Motivation

#### Framework

- Very very large number of processing elements (e.g., 2<sup>20</sup>)
- Failure-prone platform (like any realistic platform)
- Large application to be executed on the whole platform
  - ⇒ Failure(s) will certainly occur before completion!
- Resilience provided through coordinated checkpointing

#### Question

• When should we checkpoint the application?



One knows that applications should be checkpointed periodically

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#### Several proposed values for period

- Young:  $\sqrt{2 \times C \times MTBF}$  (1st order approximation)
- Daly (1):  $\sqrt{2 \times C \times (R + MTBF)}$  (1st order approximation)
- Daly (2):  $\eta \times \text{MTBF} C$ , where  $\eta = \xi^2 + 1 + \mathbb{L}(-e^{-(2\xi^2+1)})$ ,  $\xi = \sqrt{\frac{C}{2 \times \text{MTBF}}}$ , and  $\mathbb{L}(z)e^{\mathbb{L}(z)} = z$  (higher order approximation)

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How good are these approximations?

Could we find the optimal value? At least for Exponential failures? And for Weibull failures?



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  - Solving NextFailure
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  - Simulation framework
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  - Parallel jobs under synthetic failures
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# Hypotheses

- ullet Overall size of work:  ${\mathcal W}$
- Checkpoint cost: C
   (e.g., write on disk the contents of each processor memory)
- Downtime: D (hardware replacement by spare, or software rejuvenation via rebooting)
- Recovery cost after failure: R
- Homogeneous platform (same computation speeds, iid failure distributions)
- History of failures has no impact, only the time elapsed since last failure does
- A failure can happen during a checkpoint, a recovery, but not a downtime (otherwise replace D by 0 and R by R + D).

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#### Problem statement

#### Makespan

- Minimize the job's expected makespan, that is:
  - ullet the expectation  ${\mathbb E}$
  - of the time T needed to process
  - ullet a work of size  ${\mathcal W}$
  - knowing that the (single) processor failed  $\tau$  units of time ago.
- Notation:
  - ullet minimize  $\mathbb{E}(T(\mathcal{W}| au))$
  - $\omega_1(W|\tau)$ : amount of work we *attempt* to do before taking the first checkpoint

$$\mathbb{E}(T(\mathcal{W}|\tau)) =$$

$$\begin{array}{c} & \underset{\text{of success}}{\text{Probability}} \\ & \overline{\mathcal{P}_{\text{succ}}(\omega_1 + C | \tau)} (\omega_1 + C + \mathbb{E}(T(\mathcal{W} - \omega_1 | \tau + \omega_1 + C)) \\ \mathbb{E}(T(\mathcal{W} | \tau)) = & \end{array}$$

```
Time needed to compute the 1st chunk \mathcal{P}_{\text{succ}}(\omega_1 + C|\tau) \left( \overline{\omega_1 + C} + \mathbb{E} (T(\mathcal{W} - \omega_1|\tau + \omega_1 + C)) \right)
\mathbb{E}(T(\mathcal{W}|\tau)) =
```

Time needed to compute the remainder 
$$\mathcal{P}_{\text{succ}}(\omega_1 + C|\tau) \left(\omega_1 + C + \mathbb{E}(T(\mathcal{W} - \omega_1|\tau + \omega_1 + C))\right)$$

$$\mathbb{E}(T(\mathcal{W}|\tau)) =$$

$$\begin{split} \mathcal{P}_{\text{succ}} \big( \omega_1 + C | \tau \big) \big( \omega_1 + C + \mathbb{E} \big( T \big( \mathcal{W} - \omega_1 | \tau + \omega_1 + C \big) \big) \\ \mathbb{E} \big( T \big( \mathcal{W} | \tau \big) \big) &= \\ &+ \\ \big( 1 - \mathcal{P}_{\text{succ}} (\omega_1 + C | \tau ) \big) \big( \mathbb{E} \big( T_{lost} \big( \omega_1 + C | \tau \big) \big) + \mathbb{E} \big( T_{rec} \big) + \mathbb{E} \big( T \big( \mathcal{W} | R \big) \big) \big) \end{split}$$

$$\begin{split} & \mathcal{P}_{\text{succ}} \big( \omega_1 + C | \tau \big) \big( \omega_1 + C + \mathbb{E} \big( T \big( \mathcal{W} - \omega_1 | \tau + \omega_1 + C \big) \big) \\ & \mathbb{E} \big( T \big( \mathcal{W} | \tau \big) \big) = & + \\ & \underbrace{ \big( 1 - \mathcal{P}_{\text{succ}} \big( \omega_1 + C | \tau \big) \big)}_{\text{Probability of failure}} \big( \mathbb{E} \big( T_{\text{lost}} \big( \omega_1 + C | \tau \big) \big) + \mathbb{E} \big( T_{\text{rec}} \big) + \mathbb{E} \big( T \big( \mathcal{W} | R \big) \big) \big) \end{split}$$

$$\mathcal{P}_{\text{succ}}(\omega_1 + C|\tau) \left(\omega_1 + C + \mathbb{E}(T(W - \omega_1|\tau + \omega_1 + C)) \right)$$

$$\mathbb{E}(T(W|\tau)) = + \left(1 - \mathcal{P}_{\text{succ}}(\omega_1 + C|\tau)\right) \left(\mathbb{E}(T_{lost}(\omega_1 + C|\tau)) + \mathbb{E}(T_{rec}) + \mathbb{E}(T(W|R))\right)$$
Time elapsed before the failure occurred

$$\begin{split} \mathcal{P}_{\text{succ}}(\omega_1 + C|\tau) \left(\omega_1 + C + \mathbb{E}(T(\mathcal{W} - \omega_1|\tau + \omega_1 + C)) \right. \\ \mathbb{E}(T(\mathcal{W}|\tau)) = & + \\ & \left. \left(1 - \mathcal{P}_{\text{succ}}(\omega_1 + C|\tau)\right) \left(\mathbb{E}(T_{lost}(\omega_1 + C|\tau)) + \mathbb{E}(T_{rec}) + \mathbb{E}(T(\mathcal{W}|R))\right) \right. \\ & \qquad \qquad \qquad \\ & \qquad \qquad \qquad \\ \text{Time needed} \\ & \qquad \qquad \qquad \qquad \text{to perform} \\ & \qquad \qquad \qquad \qquad \text{downtime} \\ & \qquad \qquad \qquad \qquad \text{and recovery} \end{split}$$

$$\begin{split} \mathcal{P}_{\text{succ}} \big( \omega_1 + C | \tau \big) \big( \omega_1 + C + \mathbb{E} \big( \mathcal{T} \big( \mathcal{W} - \omega_1 | \tau + \omega_1 + C \big) \big) \\ \mathbb{E} \big( \mathcal{T} \big( \mathcal{W} | \tau \big) \big) &= \\ &+ \\ \big( 1 - \mathcal{P}_{\text{succ}} \big( \omega_1 + C | \tau \big) \big) \big( \mathbb{E} \big( \mathcal{T}_{lost} \big( \omega_1 + C | \tau \big) \big) + \mathbb{E} \big( \mathcal{T}_{rec} \big) + \mathbb{E} \big( \mathcal{T} \big( \mathcal{W} | R \big) \big) \big) \end{split}$$

Problem: finding  $\omega_1(\mathcal{W}, \tau)$  minimizing  $\mathbb{E}(T(\mathcal{W}|\tau))$ 

# Failures following an exponential distribution

#### **Theorem**

Optimal strategy splits  $\mathcal{W}$  into  $K^*$  same-size chunks where

$$K^* = \mathsf{max}(1, \lfloor K_0 \rfloor)$$
 or  $K^* = \lceil K_0 \rceil$ 

(whichever leads to the smaller value)

where

$$K_0 = rac{\lambda \mathcal{W}}{1 + \mathbb{L}(-e^{-\lambda C - 1})}$$
 and  $\mathbb{L}(z)e^{\mathbb{L}(z)} = z$ 

Optimal expectation of makespan is

$$K^*\left(e^{\lambda R}\left(\frac{1}{\lambda}+D\right)\right)\left(e^{\lambda\left(\frac{\mathcal{W}}{K^*}+C\right)}-1\right)$$

# Arbitrary failure distributions

$$\mathbb{E}(T(\mathcal{W}|\tau)) = \min_{0 < \omega_1 \le \mathcal{W}} \begin{pmatrix} P_{suc}(\omega_1 + C|\tau) \Big( \omega_1 + C + \mathbb{E}(T(\mathcal{W} - \omega_1|\tau + \omega_1 + C)) \Big) \\ + (1 - P_{suc}(\omega_1 + C|\tau)) \times \\ (\mathbb{E}(T_{lost}(\omega_1 + C|\tau)) + \mathbb{E}(T_{rec}) + \mathbb{E}(T(\mathcal{W}|R))) \end{pmatrix}$$

#### Solve via dynamic programming

- Time quantum u: all chunk sizes  $\omega_i$  are integer multiples of u
- Trade-off: accuracy versus higher computing time

# Dynamic programming

#### **Algorithm 1:** DPMAKESPAN $(x,b,y,\tau_0)$

```
if x = 0 then
     return 0
if solution[x][b][y] = unknown then
     best \leftarrow \infty; \tau \leftarrow b\tau_0 + yu
     for i = 1 to x do
          exp\_succ \leftarrow first(DPMakespan(x - i, b, y + i + \frac{C}{i}, \tau_0))
          exp_fail \leftarrow first(DPMakespan(x, 0, \frac{R}{t}, \tau_0))
          cur \leftarrow P_{suc}(iu + C|\tau)(iu + C + exp\_succ)
                +(1-P_{suc}(iu+C|\tau))\Big(\mathbb{E}(T_{lost}(iu+C,\tau))\Big)
                                                  +\mathbb{E}(T_{rec}) + exp_{-}fail
          if cur < best then
                best \leftarrow cur; chunksize \leftarrow i
     solution[x][b][y] \leftarrow (best, chunksize)
return solution[x][b][y]
```

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#### Problem statement

#### NEXTFAILURE

- Maximize expected amount of work completed before next failure
- Optimization on a "failure-by-failure" basis
- ullet Hopefully a good approximation, at least for large job sizes  ${\mathcal W}$

# Approach

$$\mathbb{E}(W(\omega|\tau)) = P_{suc}(\omega_1 + C|\tau)(\omega_1 + \mathbb{E}(W(\omega - \omega_1|\tau + \omega_1 + C)))$$

#### Proposition

$$\mathbb{E}(W(\mathcal{W}|0)) = \sum_{i=1}^{K} \omega_i \times \prod_{j=1}^{i} P_{suc}(\omega_j + C|t_j)$$

where  $t_j = \sum_{\ell=1}^{j-1} \omega_\ell + C$  is the total time elapsed (without failure) before execution of chunk  $\omega_I$ , and K is the (unknown) target number of chunks.

# Solving through dynamic programming

### **Algorithm 2:** DPNEXTFAILURE $(x, n, \tau_0)$

```
if x = 0 then
    return 0
if solution[x][n] = unknown then
    best \leftarrow \infty
    \tau \leftarrow \tau_0 + (\mathcal{W} - xu) + nC
    for i = 1 to x do
          work = first(DPNEXTFAILURE(x - i, n + 1, \tau_0))
         cur \leftarrow P_{suc}(iu + C|\tau) \times (iu + work)
         if cur < best then
              best \leftarrow cur: chunksize \leftarrow i
    solution[x][n] \leftarrow (best, chunksize)
return solution[x][n]
```

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(whichever leads to the smaller value)

where 
$$K_0(p) = \frac{\lambda \mathcal{W}(p)}{1 + \mathbb{L}(-e^{-p\lambda C - 1})}$$
 and  $\mathbb{L}(z)e^{\mathbb{L}(z)} = z$ 

Optimal expectation of makespan is

$$\mathcal{K}^*(p)\left(rac{1}{p\lambda}+\mathbb{E}(\mathcal{T}_{rec}(p))
ight)\left(\mathrm{e}^{\lambda\left(rac{\mathcal{W}}{\mathcal{K}^*(p)}+p\mathcal{C}
ight)}-1
ight)$$



# Arbitrary failure distributions

- Cannot solve analytically the recursion
- Cannot extend the dynamic programming algorithm
   DPMAKESPAN designed for the single-processor case:
  - Would need to memorize all possible failure scenarios for each processor
  - Number of states exponential in p

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# Dynamic programming

All au variables evolve identically: recursive calls only correspond to cases in which no failure has occurred.

$$\mathbb{E}(W(W|\tau_1,\ldots,\tau_p)) = P_{suc}(\omega_1+C|\tau_1,\ldots,\tau_p)(\omega_1+\mathbb{E}(W(W-\omega_1|\tau_1+\omega_1+C,\ldots,\tau_p+\omega_1+C)))$$

- ⇒ Same dynamic programming approach than previously
  - Linear dependency in p (computation of  $P_{suc}$ )
  - Reduce complexity by recording only x most recent  $\tau$  values and approximate the other values using y rounding values defined by x regularly-spaced quantiles

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#### Evaluated approaches

#### Heuristics

- Young [4]
- DalyLow [2]
- DalyHigh [2]
- Bouguerra [1]
- Liu [3]
- OPTEXP
- DPMakespan
- DPNextFailure

#### Theoretical bounds

- LOWERBOUND (omniscient algorithm)
- PeriodLB



# Synthetic failure distributions

	p <sub>total</sub>	D	C,R	MTBF	$\mathcal{W}$
1-proc	1	60 s	600 s	1 h, 1 d, 1 w	20 d
Petascale	45, 208	60 s	600 s	125 y, 500 y	1,000 y
Exascale	2 <sup>20</sup>	60 s	600 s	1250 y	10,000 y

Simulation parameters

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### Sequential jobs under Exponential failures

	MTBF		
Heuristics	1 hour	1 day	1 week
LowerBound	0.62865	0.90714	0.979151
PERIODLB	1.00705	1.01588	1.02298
Young	1.01635	1.01590	1.02332
DalyLow	1.02711	1.01611	1.02338
DalyHigh	1.00700	1.01592	1.02373
Liu	1.01607	1.01655	1.02333
Bouguerra	1.02562	1.02329	1.02685
ОртЕхр	1.00705	1.01611	1.02298
DPNEXTFAILURE	1.00785	1.01699	1.02851
DPMakespan	1.00737	1.01655	1.03467

Degradation from best, single processor, Exponential failures

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Degradation from best, single processor, Exponential failures

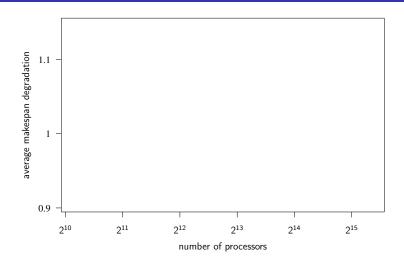
### Sequential jobs under Weibull failures

	MTBF		
Heuristics	1 hour	1 day	1 week
LowerBound	0.66417	0.90714	0.97915
PeriodLB	1.00960	1.01588	1.02298
Young	1.00965	1.01590	1.02332
DalyLow	1.01155	1.01611	1.02338
DalyHigh	1.01785	1.01592	1.02373
Liu	1.00914	1.01655	1.02333
Bouguerra	1.02936	1.02329	1.02685
ОртЕхр	1.01788	1.01611	1.02298
DPNEXTFAILURE	1.01408	1.01699	1.02851
DPMakespan	1.00731	1.01655	1.03467

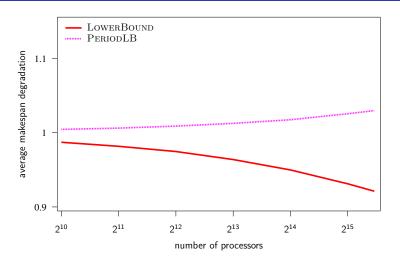
Degradation from best, single processor, Weibull failures

#### Outline

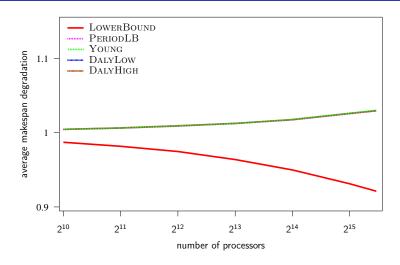
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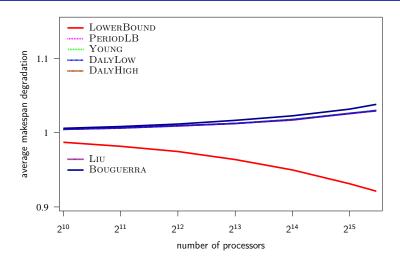
Petascale, MTBF = 125 years



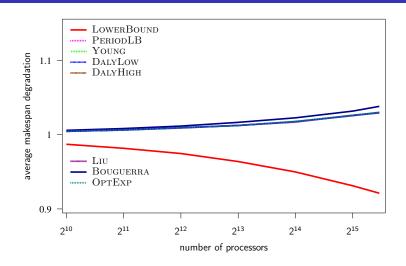
Petascale, MTBF = 125 years



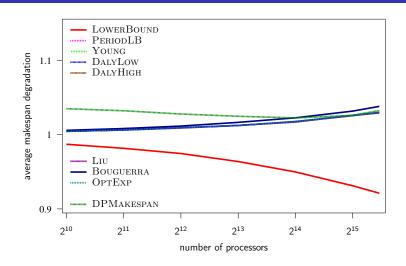
Petascale, MTBF = 125 years



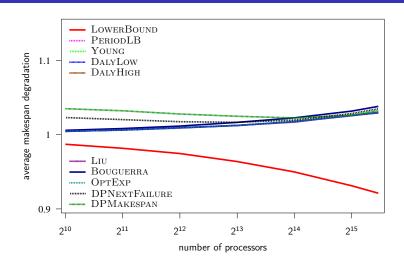
Petascale, MTBF = 125 years



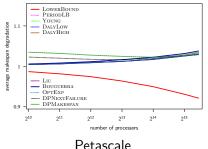
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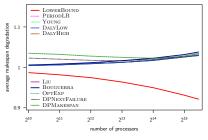
Petascale, MTBF = 125 years



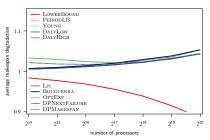
MTBF = 125 years

LOWERBOUND PERIODLB YOUNG average makespan degradation BOUGUERRA OPTEXP ...... DPNEXTFAILURE ---- DPMakespan 213 211 215 number of processors

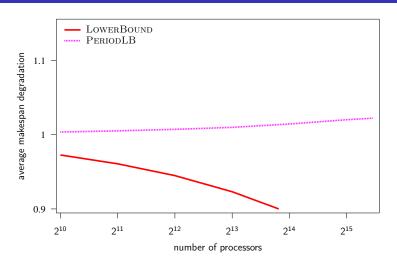
> Petascale MTBF = 500 years



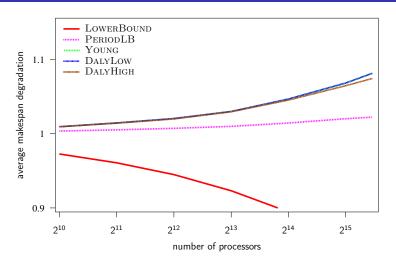
 $\begin{array}{c} {\sf Petascale} \\ {\sf MTBF} = 125 \; {\sf years} \end{array}$ 



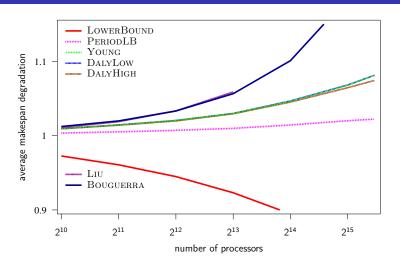
 $\begin{aligned} &\mathsf{Exascale}\\ &\mathsf{MTBF} = 1250 \; \mathsf{years} \end{aligned}$ 



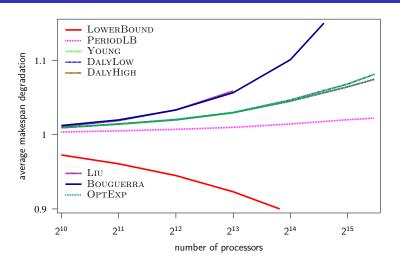
Petascale, MTBF = 125 years, k = 0.70



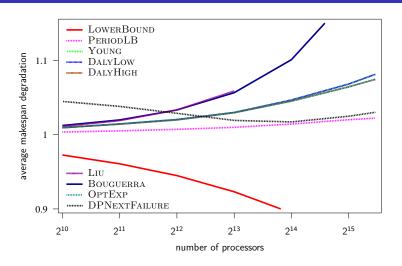
Petascale, MTBF = 125 years, k = 0.70



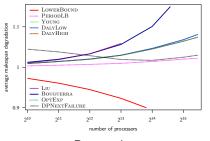
Petascale, MTBF = 125 years, k = 0.70

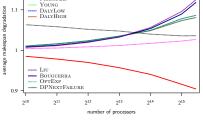


Petascale, MTBF = 125 years, k = 0.70



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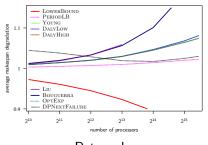


LOWERBOUND

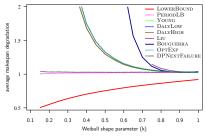
PERIODLB

 $\begin{array}{c} \text{Petascale} \\ \text{MTBF} = 125 \text{ years} \\ \text{k} = 0.70 \end{array}$ 

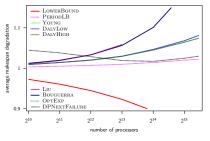
 $\begin{aligned} & \text{Petascale} \\ & \text{MTBF} = 500 \text{ years} \\ & \text{k} = 0.70 \end{aligned}$ 

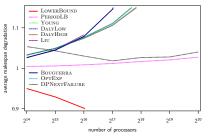


 $\begin{array}{c} \text{Petascale} \\ \text{MTBF} = 125 \text{ years} \\ \text{k} = 0.70 \end{array}$ 



Petascale MTBF = 125 years 45,208 processors



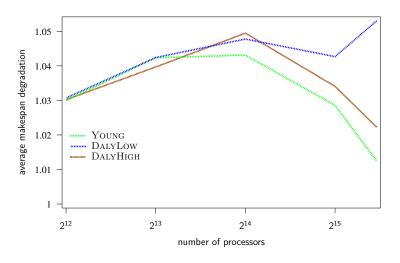


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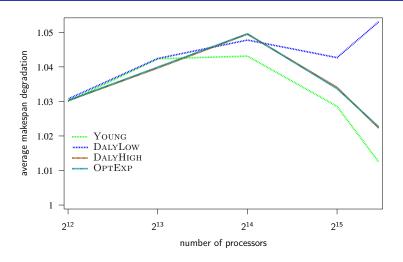
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  - Solving NEXTFAILURE
- 3 Experiments
  - Simulation framework
  - Sequential jobs under synthetic failures
  - Parallel jobs under synthetic failures
  - Parallel jobs under trace-based failures
- 4 Conclusion

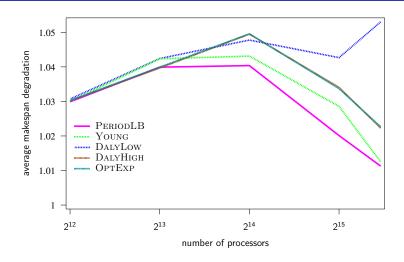


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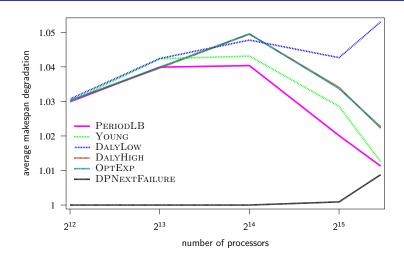




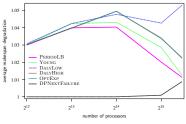
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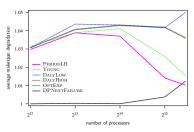
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#### Outline

- Single-processor jobs
  - Solving Makespan
  - Solving NextFailure
- Parallel jobs
  - Solving Makespan
  - Solving NEXTFAILURE
- 3 Experiments
  - Simulation framework
  - Sequential jobs under synthetic failures
  - Parallel jobs under synthetic failures
  - Parallel jobs under trace-based failures
- 4 Conclusion

#### Conclusion and perspectives

- Complete analytical solution for Makespan/ Exponential
- Dynamic programming algorithms for NEXTFAILURE / Arbitrary distribution
- Makespan decreased by DPNEXTFAILURE (for the hardest cases)
- Future work

Target non-coordinated checkpointing (e.g., hierarchical checkpointing with message logging)

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